



DC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC
Input High Voltage (for JTAG and GPIO)
Input High Voltage (all other pins)
Input Low Voltage
EXTAL and EXTCLK Input High Voltage
Input Leakage Current, $V_{IN} = 5.5\text{ V}$
Hi-z (Off State) Leakage Current, $V_{IN} = 3.5\text{ V}$
Signal Low Input Current, $V_{IL} = 0.8\text{ V}$
Signal High Input Current, $V_{IH} = 2.0\text{ V}$
Output High Voltage, $I_{OH} = -2.0\text{ mA}$, $V_{DDH} = 3.0\text{ V}$ Except XTAL, XFC, and Open-Drain Pins
Output Low Voltage IOL = 2.0 mA CLKOUT IOL = 3.2 mA [6:31], TSIZ0/REG, TSIZ1, D(0:31), DP[0:31], RD/WR, BURST, RSV/IRQ2, IP_B[0:1]/IWP[0:1]/VFLS, IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IF_VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, USBRXD/PA1, PA13, SMRXD2/L1TXDA/PA9, SMTXD2/L1RXDA/PA8, SPKROUT, TIN1/L1RCLKA/BRGO1/CLK1/PA7, TIN3/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, TIN4/T, PA4, LCD_A/SPISEL/PB31, SPICLK/TXD3/PB30, SPII, PB29, BRGO3/SPIMISO/PB28, BRGO1/I2CSDA/PB27, I2CSCL/PB26, SMTXD1/TXD3/PB25, SMRXD1/RXD3, SMSYN1/SDACK1/CTS3/PB23, SMSYN2/SDACK2/PE, L1ST1/PB19, L1ST2/RTS2/PB18, LCD_C/L1ST3/PB17, L1RQA/PB16, L1ST5/DREQ1/PC15, L1ST6/RTS2/DRI, L1ST7/RTS3/PC13, L1ST8/L1RQA/PC12, USBRXP/P, USBRXN/TGATE1/PC10, CTS2/PC9, TGATE1/CD2/P, PC7, USBTXN/PC6, SDACK1/L1TSYNCA/PC5, L1RS, PC4, LD8/VD7/PD15, LD7/VD6/PD14, LD6/VD5/PD13, PD12, LD4/VD3/PD11, LD3/VD2/PD10, LD2/VD1/PD9, PD8, FRAME/VSYNCPD5, LCD_AC/LOE/BLANK/PD6, FIELD/PD7, LOAD/HSYNCPD4, SHIFT/CLK/PD3
IOL = 5.3 mA [BDIP/GPL_B5, BR, BG, FRZ/IRQ6, CS[0:31], CE1_B, CS7/CE2_B, WE0/BS_AB0/IORD, WE1/BS_A, WE2/BS_AB2/PCOE, WE3/BS_AB3/PCWE, GPL_A0/AS, GPL_A1/GPL_B1, GPL_A[2:3]/GPL_B[2:3]/CS[2:3], UF, PD12, LD4/VD3/PD11, LD3/VD2/PD10, LD2/VD1/PD9, PD8, FRAME/VSYNCPD5, LCD_AC/LOE/BLANK/PD6, FIELD/PD7, LOAD/HSYNCPD4, SHIFT/CLK/PD3
IOL = 7.0 mA USBOE/PA14, TXD2/PA12
IOL = 8.9 mA TS, TA, TEA, BI, BB, HRESET, SRESET

NOTE: Input pin voltage specifications are $V_{CC} = +4\text{ V}$ \n AC timings are based on a 50 pF load. \n If you are using Mask Revision Base #F98S, a

MPC823 Electrical Specifications

This document contains detailed information on electrical characteristics, and AC timing specifications.



Note: Visit our website at www.freescale.com for more information. \n For frequencies greater than 25, 40, or 50MHz. Our AC timing specifications are calculated based on a 50 pF load.

This device contains circuitry protecting against electrostatic discharge (ESD) fields. However, it is advised that precautions be taken to avoid voltages higher than the maximum-rated voltages to the device. This protection is enhanced if unused inputs are tied to an appropriate voltage level.

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MAXIMUM RATINGS (GND = 0V)

RATING
Supply Voltage
Input Voltage (JTAG and GPIO)
Input Voltage (All other pins)
Operating Temperature
Storage Temperature Range
NOTES:
<ol style="list-style-type: none"> Functional operating conditions are = 3.0 - 3.6 V. Absolute maximum at the maxima is not guaranteed. S cause permanent damage to the d CAUTION: The JTAG and GPIO in supply voltage, this restriction appl 5 Volt friendly inputs are inputs tha If you are using Mask Revision Bas are 5V tolerant inputs.

THERMAL CHARACTERISTICS

CHARACTERISTIC
Thermal Resistance for BGA

POWER CONSIDERATIONS

The average chip-junction temperature, T_J , in

$$T_J = T_A + (P_D \cdot q_{JA}) \quad (1)$$

where

T_A = Ambient Temperature, °C

q_{JA} = Package Thermal Resis

P_D = $P_{INT} + P_{I/O}$

P_{INT} = $I_{DD} \times V_{DD}$, Watts—Chip I

$P_{I/O}$ = Power Dissipation on In

For most applications $P_{I/O} < 0.3 \cdot P_{INT}$ and can relationship between P_D and T_J is:

$$P_D = K \Pi (T_J + 273^\infty C) \quad (2)$$

Solving equations (1) and (2) for K gives

$$K = \frac{P_D}{(T_A + 273^\infty C) + q_{JA}}$$

where K is a constant pertaining to the partic by measuring P_D (at equilibrium) for a known can be obtained by solving equations (1) and

Layout Practices

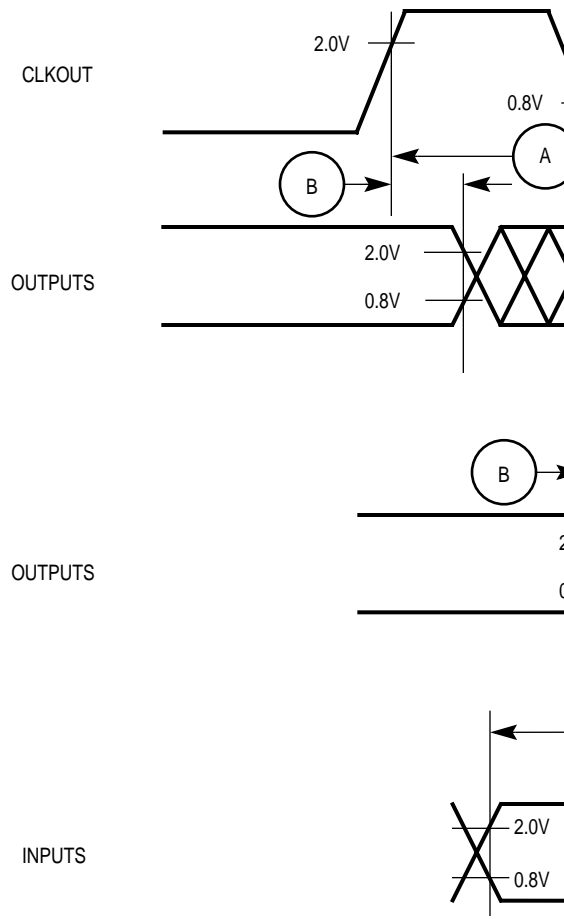
Each V_{CC} pin on the MPC823 should be prov supply. Each GND pin should be provided w supply pins drive distinct groups of logic on c ground using at least four 0.1 μF bypass cap sides of the package. The capacitor leads an chip V_{CC} and GND should be kept to less tha board that employs two inner layers as V_{CC} a

All output pins on the MPC823 have fast rise interconnection length should be minimized caused by these fast output switching times. address and data busses. Maximum PC trac Capacitance calculations should consider all due to the PC traces. Attention to proper PCB in systems with higher capacitive loads beca in the V_{CC} and GND circuits. Pull up all unuse Special care should be taken to minimize the

Table 1. Bus Opera

NUM	CHARACTERISTIC
B28c	CLKOUT Falling Edge to $\overline{WE}(0:3)$ Negated -GPCM Access $TRLX = '0'$, $CSNT = '1'$, $EBDF=1$
B28d	CLKOUT Falling Edge to \overline{CS} Negated -GPCM-Wri $TRLX = '0'$, $CSNT = '1'$, $ACS = '10'$ or $ACS='11'$, E
B29	$\overline{WE}(0:3)$ Negated to D(0:31), DP(0:3) Hi Z -GPCM Access, $CSNT = '0'$
B29a	$\overline{WE}(0:3)$ Negated to D(0:31), DP(0:3) Hi Z -GPCM Access, $TRLX = '0'$, $CSNT = '1'$, $EBDF = 0$
B29b	\overline{CS} Negated to D(0:31), DP(0:3) Hi Z -GPCM- Wri $ACS = '00'$, $TRLX = '0'$ & $CSNT = '0'$
B29c	\overline{CS} Negated to D(0:31), DP(0:3) Hi Z -GPCM- Wri $TRLX = '0'$, $CSNT = '1'$, $ACS = '10'$ or $ACS='11'$, E
B29d	$\overline{WE}(0:3)$ Negated to D(0:31), DP(0:3) Hi Z -GPCM Access, $TRLX = '1'$, $CSNT = '1'$, $EBDF = 0$
B29e	\overline{CS} Negated to D(0:31), DP(0:3) Hi Z -GPCM- Wri $TRLX = '1'$, $CSNT = '1'$, $ACS = '10'$ or $ACS='11'$, E
B29f	$\overline{WE}(0:3)$ Negated to D(0:31), DP(0:3) Hi Z -GPCM Access, $TRLX = '0'$, $CSNT = '1'$, $EBDF = 1$
B29g	\overline{CS} Negated to D(0:31), DP(0:3) Hi Z -GPCM- Wri $TRLX = '0'$, $CSNT = '1'$, $ACS = '10'$ or $ACS='11'$, E
B29h	$\overline{WE}(0:3)$ Negated to D(0:31), DP(0:3) Hi Z -GPCM Access, $TRLX = '1'$, $CSNT = '1'$, $EBDF = 1$
B29i	\overline{CS} Negated to D(0:31), DP(0:3) Hi Z -GPCM- Wri $TRLX = '1'$, $CSNT = '1'$, $ACS = '10'$ or $ACS='11'$, E
B30	\overline{CS} , $\overline{WE}(0:3)$ Negated to A(6:31) invalid -GPCM- V Access.
B30a	$\overline{WE}(0:3)$ Negated to A(6:31) Invalid -GPCM- Write $TRLX='0'$, $CSNT = '1'$. \overline{CS} Negated to A(6:31) Inval Write Access, $TRLX='0'$, $CSNT = '1'$, $ACS = 10$, AC $EBDF = 0$
B30b	$\overline{WE}(0:3)$ Negated to A(6:31) Invalid -GPCM- Write $TRLX='1'$, $CSNT = '1'$. \overline{CS} Negated to A(6:31) Inval Write Access, $TRLX='1'$, $CSNT = '1'$, $ACS = 10$, AC $EBDF = 0$
B30c	$\overline{WE}(0:3)$ Negated to A(6:31) Invalid -GPCM- Write $TRLX='0'$, $CSNT = '1'$. \overline{CS} Negated to A(6:31) Inval Write Access, $TRLX='0'$, $CSNT = '1'$, $ACS = 10$, AC $EBDF = 1$
B30d	$\overline{WE}(0:3)$ Negated to A(6:31) Invalid -GPCM- Write $TRLX='1'$, $CSNT = '1'$. \overline{CS} Negated to A(6:31) Inval Write Access, $TRLX='1'$, $CSNT = '1'$, $ACS = 10$, AC $EBDF = 1$
B31	CLKOUT Falling Edge to \overline{CS} valid as requested by the corresponding word of the UPM

AC ELECTRICAL CHARACTERISTICS



A = MAXIMUM OUTPUT DELAY SPECIFICATION
 B = MINIMUM OUTPUT HOLD TIME

EXTERNAL BUS ELECTRICAL CHA

Table 1. Bus Opera

Table 1. Bus

NUM	CHARACTERISTIC
B1	CLKOUT Period
B1a	EXTCLK to CLKOUT Phase Skew (EXTCLK>15MF MF ≤ 2)
B1b	EXTCLK to CLKOUT Phase Skew (EXTCLK>10MF MF ≤ 10)
B1c	CLKOUT Phase Jitter (EXTCLK>15MHz and MF≤
B1d	CLKOUT Phase Jitter (EXTCLK>10MHz and MF≤
B1e	CLKOUT Frequency Jitter (MF<10)
B1f	CLKOUT Frequency Jitter (10<MF<500)
B1g	CLKOUT Frequency Jitter (MF>500)
B1h	Frequency Jitter on EXTCLK
B2	Clock Pulse Width Low
B3	Clock Pulse Width High
B4	CLKOUT Rise Time
B5	CLKOUT Fall Time
B6	N/A (Used on Interactive Spreadsheet)
B7	CLKOUT to A(6:31), RD/WR, BURST, D(0:31), DF Invalid
B7a	CLKOUT to TSIZ(0:1),REG, RSV, AT(0:3),BDIP, F
B7b	CLKOUT to BR, BG, FRZ, VFLS(0:1), VF(0:2), IWP LWP(0:1), STS Invalid
B8	CLKOUT to A(6:31), RD/WR, BURST, D(0:31), DF
B8a	CLKOUT to TSIZ(0:1),REG, RSV, AT(0:3), BDIP, I
B8b	CLKOUT to BR, BG, VFLS(0:1), VF(0:2), IWP(0:2), LWP(0:1), STS Valid
B9	CLKOUT to A(6:31), RD/WR, BURST, D(0:31), DF TSIZ(0:1),REG, RSV, AT(0:3), PTR Hi Z
B10	N/A
B11	CLKOUT to TS, BB Assertion
B11a	CLKOUT to TA, BI Assertion (when driven by the Memory Controller or PCMCIA Interface)
B12	CLKOUT to TS, BB Negation
B12a	CLKOUT to TA, BI Negation (when driven by the Memory Controller or PCMCIA Interface)
B13	CLKOUT to TS, BB Hi Z

NUM	CHARACTERISTIC
B13a	CLKOUT to TA, BI Hi Z (When Driven by the Mem Controller or PCMCIA Interface)
B14	CLKOUT to TEA Assertion
B15	CLKOUT to TEA Hi Z
B16	TA, BI Valid to CLKOUT (Setup Time)
B16a	TEA, KR, RETRY Valid to CLKOUT (Setup Time)
B16b	BB, BG, BR Valid to CLKOUT (Setup Time)
B17	CLKOUT to TA, TEA, BI, BB, BG, BR Valid (Hold
B17a	CLKOUT to KR, RETRY Valid (Hold Time)
B18	D(0:31), DP(0:3) Valid to CLKOUT Rising Edge (S
B19	CLKOUT Rising Edge to D(0:31), DP(0:3) Valid (H
B20	D(0:31), DP(0:3) Valid to CLKOUT Falling Edge (S
B21	CLKOUT Falling Edge to D(0:31), DP(0:3) Valid (H
B22	CLKOUT Rising Edge to CS Asserted -GPCM- AC
B22a	CLKOUT Falling Edge to CS Asserted -GPCM- AC TRLX = 0
B22b	CLKOUT Falling Edge to CS Asserted -GPCM- AC TRLX = 0, EBDF = 0
B22c	CLKOUT Falling Edge to CS Asserted -GPCM- AC TRLX = 0, EBDF = 1
B23	CLKOUT Rising Edge to CS Negated -GPCM-Read GPCM-Write Access, ACS=00, TRLX=0, CSNT=0
B24	A(6:31) to CS Asserted -GPCM- ACS = 10, TRLX
B24a	A(6:31) to CS Asserted -GPCM- ACS = 11, TRLX
B25	CLKOUT Rising Edge to OE, WE(0:3) Asserted
B26	CLKOUT Rising Edge to OE Negated
B27	A(6:31) to CS Asserted -GPCM- ACS = 10, TRLX
B27a	A(6:31) to CS Asserted -GPCM- ACS = 11, TRLX
B28	CLKOUT Rising Edge to WE(0:3) Negated -GPCM Access CSNT = '0'
B28a	CLKOUT Falling Edge to WE(0:3) Negated -GPCM Access TRLX = '0', CSNT = '1', EBDF=0
B28b	CLKOUT Falling Edge to CS Negated -GPCM-Write TRLX = '0', CSNT = '1', ACS = '10' or ACS='11', E

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Table 1. Bus Opera

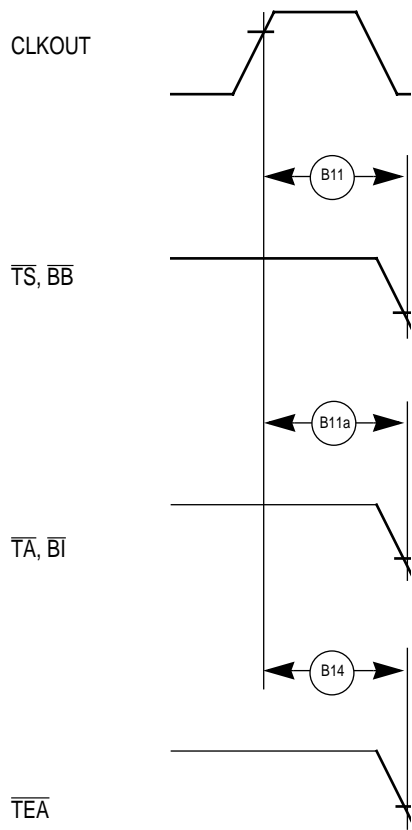


Figure 3. Synchronous A Outputs Signa

NUM	CHARACTERISTIC
B31a	CLKOUT Falling Edge to \overline{CS} valid as requested by the corresponding word of the UPM, EBDF = 0
B31b	CLKOUT Rising Edge to \overline{CS} valid as requested by the corresponding word of the UPM
B31c	CLKOUT Rising Edge to \overline{CS} valid as requested by the corresponding word of the UPM
B31d	CLKOUT Falling Edge to \overline{CS} valid as requested by the corresponding word of the UPM, EBDF = 1
B32	CLKOUT Falling Edge to \overline{BS} valid as requested by the corresponding word of the UPM
B32a	CLKOUT Falling Edge to \overline{BS} valid as requested by the corresponding word of the UPM, EBDF = 0
B32b	CLKOUT Rising Edge to \overline{BS} valid as requested by the corresponding word of the UPM
B32c	CLKOUT Rising Edge to \overline{BS} valid as requested by the corresponding word of the UPM
B32d	CLKOUT Falling Edge to \overline{BS} valid as requested by the corresponding word of the UPM, EBDF = 1
B33	CLKOUT Falling Edge to \overline{GPL} valid as requested by the corresponding word of the UPM
B33a	CLKOUT Rising Edge to \overline{GPL} valid as requested by the corresponding word of the UPM
B34	A(6:31) and D(0:31) to \overline{CS} valid as requested by the corresponding word of the UPM
B34a	A(6:31) and D(0:31) to \overline{CS} valid as requested by the corresponding word of the UPM
B34b	A(6:31) and D(0:31) to \overline{CS} valid as requested by the corresponding word of the UPM
B35	A(6:31) and D(0:31) to \overline{BS} valid as requested by the corresponding word of the UPM
B35a	A(6:31) and D(0:31) to \overline{BS} valid as requested by the corresponding word of the UPM
B35b	A(6:31) and D(0:31) to \overline{BS} valid as requested by the corresponding word of the UPM
B36	A(6:31) and D(0:31) to \overline{GPL} valid as requested by the corresponding word of the UPM
B37	UPWAIT Valid to CLKOUT Falling Edge
B38	CLKOUT Falling Edge to UPWAIT Valid
B39	\overline{AS} Valid to CLKOUT Rising Edge

Table 1. Bus Opera

NUM	CHARACTERISTIC
B40	A(6:31), TSIZ(0:1), RD/WR, BURST, Valid to CLKC Edge
B41	TS Valid to CLKOUT Rising Edge (Setup Time)
B42	CLKOUT Rising Edge to TS Valid (Hold Time)
B43	AS Negation to Memory Controller Signals Negati

NOTES:

1. The timing for \overline{BR} output is relevant when tl
The timing for \overline{BG} output is relevant when tl
2. The setup times required for \overline{TA} , \overline{TEA} and \overline{B}
(and not when the memory controller or the
3. The timing required for \overline{BR} input is relevant v
The timing for \overline{BG} input is relevant when the
4. The D(0:31) and DP(0:3) input timings B18
input signal is asserted.
5. The D(0:31) and DP(0:3) input timings B20
valid only under control of the UPM in the r
6. The timing B30 refers to \overline{CS} when ACS = '0
7. The signal UPWAIT is considered asynchro
specified in B37 and B38 are specified to ei
8. The \overline{AS} signal is considered asynchronous

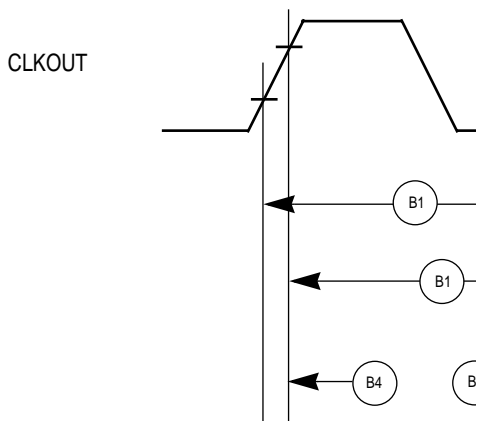


Figure 1. External

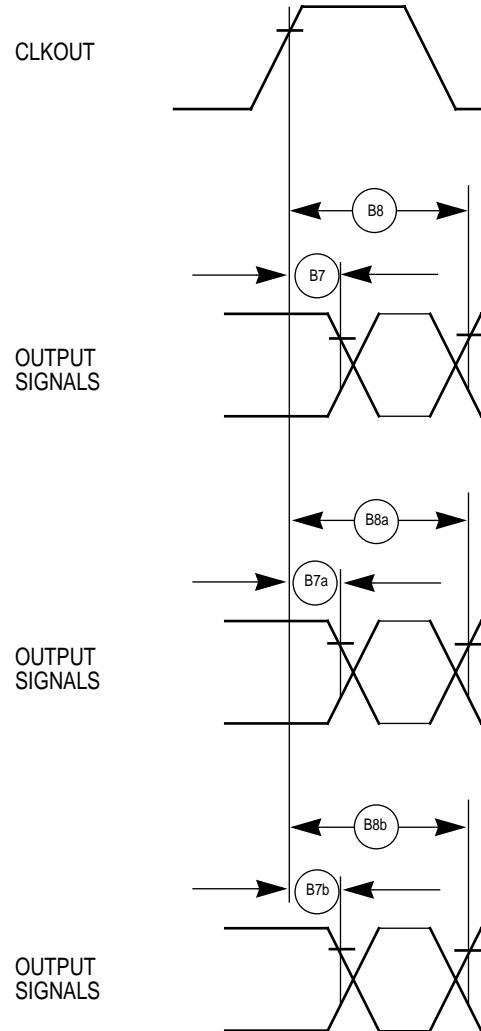


Figure 2. Synchronous O

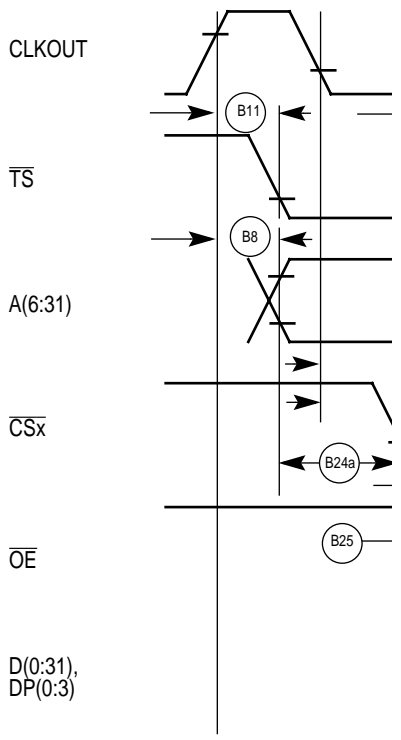


Figure 9. External B (GPCM Controlled)

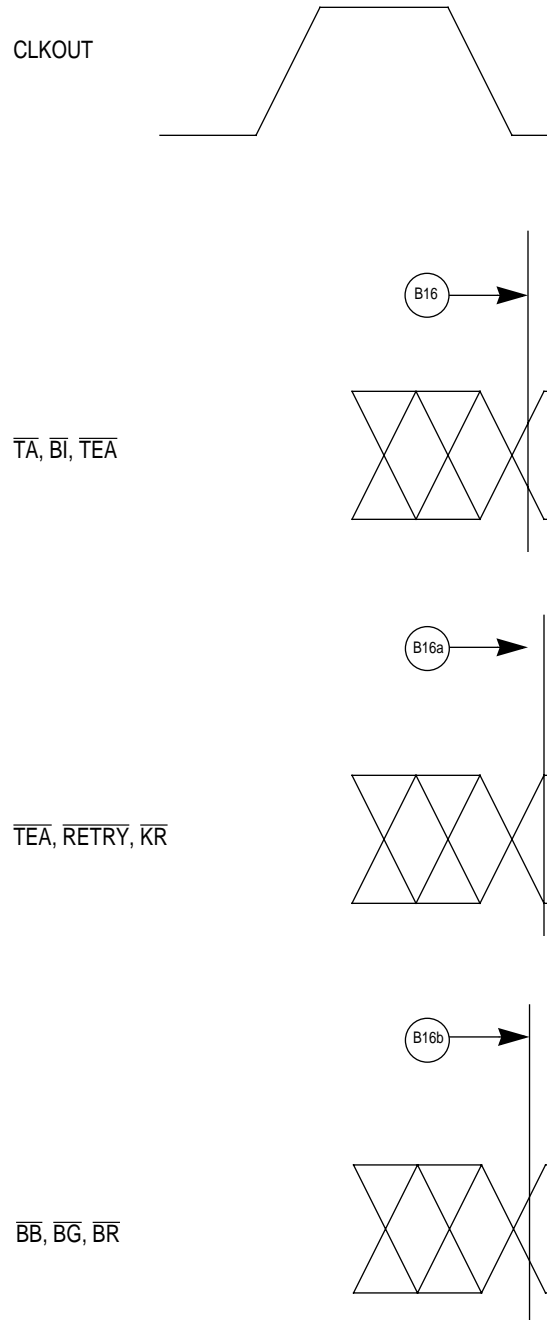


Figure 4. Synchronous I/O

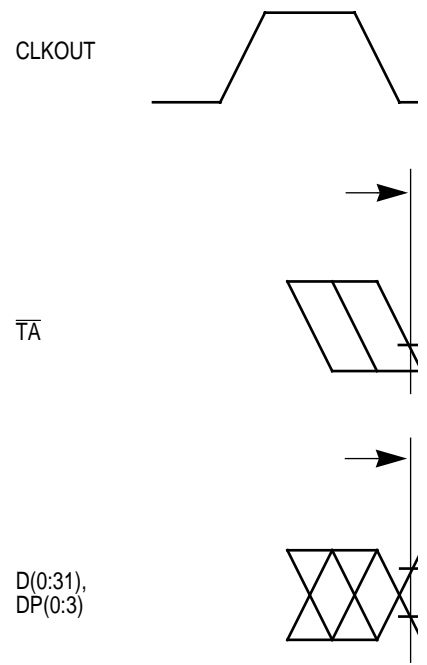


Figure 5. Input Data In N

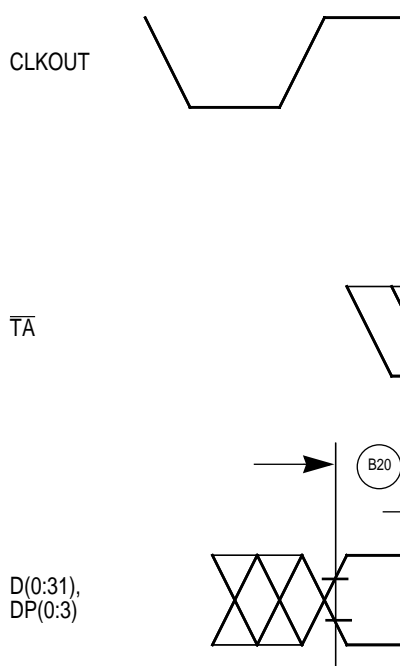


Figure 6. Input Data When Con

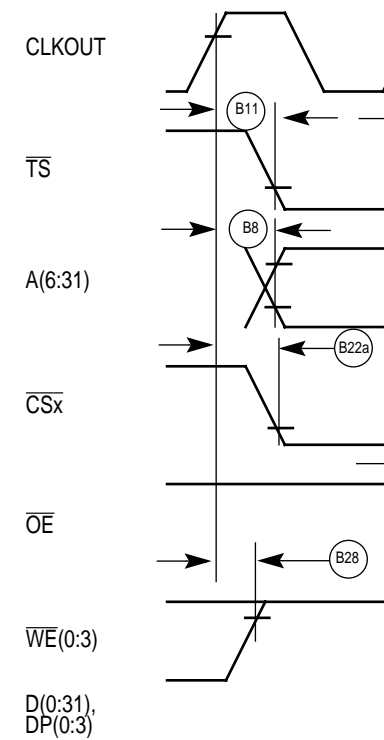


Figure 7. External Bus Read Timing

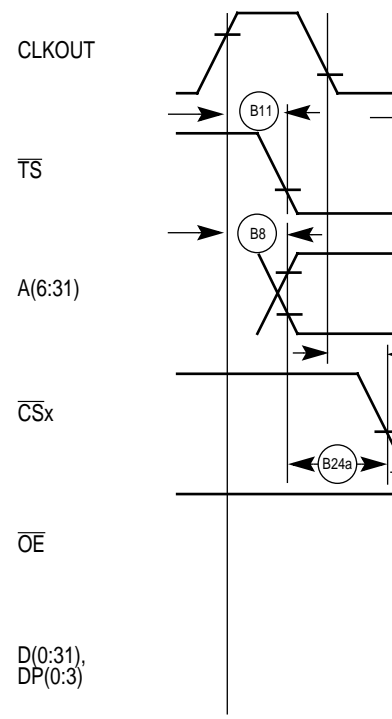


Figure 8. External Bus Read Timing Diagram

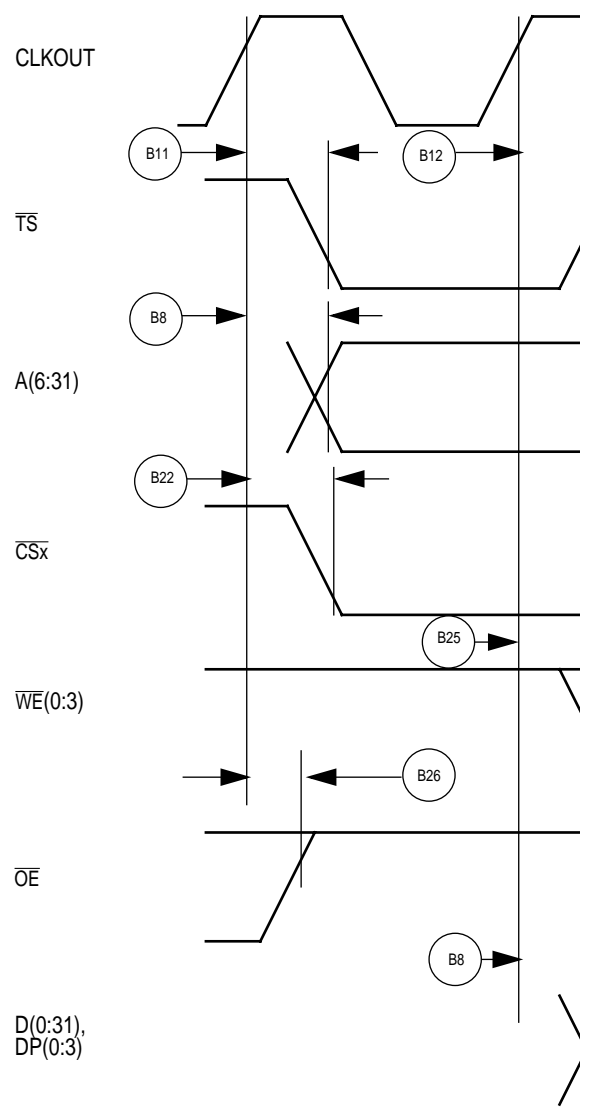


Figure 13. External E (GPCM Controlled-TRLX)

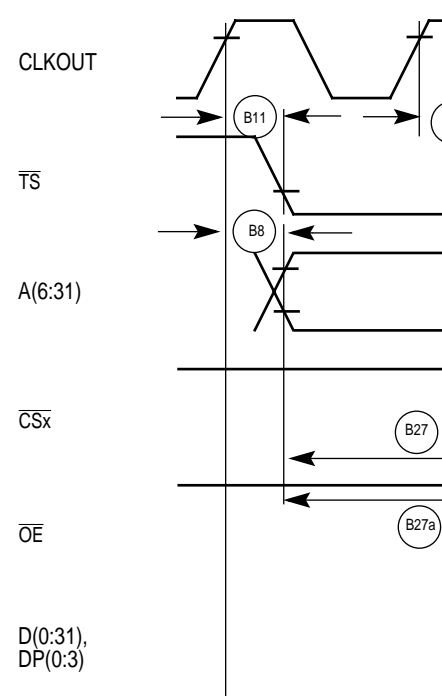


Figure 10. External E (GPCM Controlled-TRLX)

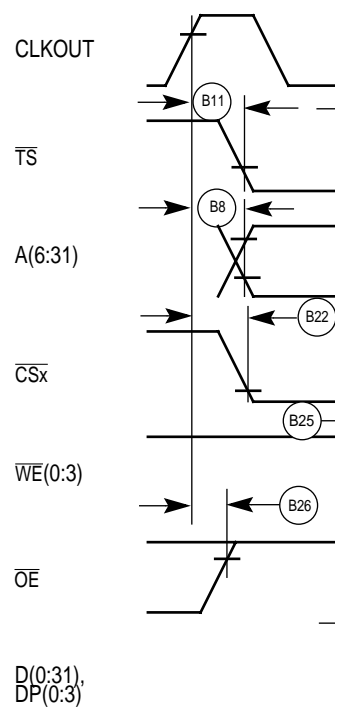


Figure 11. External E (GPCM Controlled-

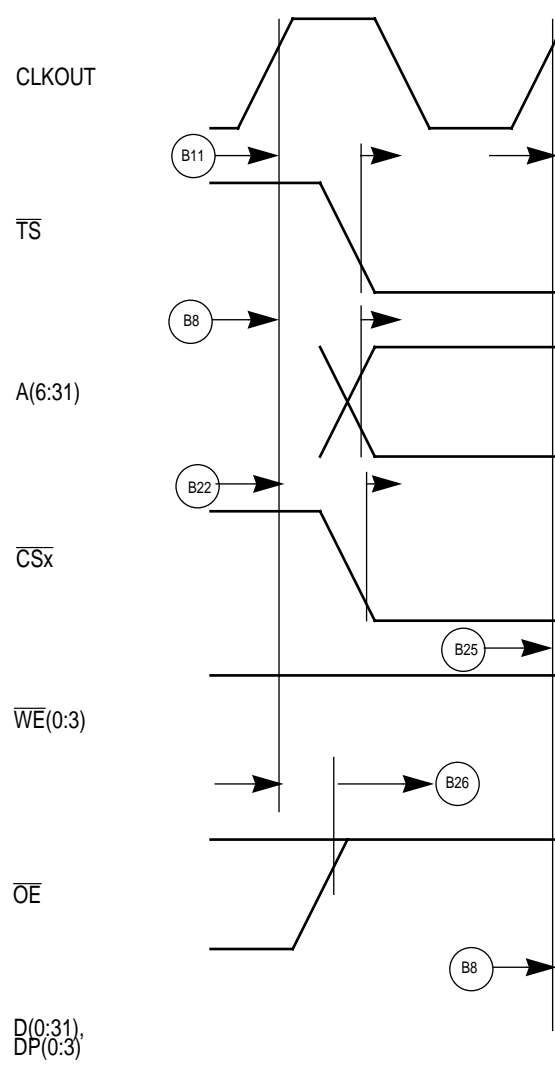


Figure 12. External E (GPCM Controlled-

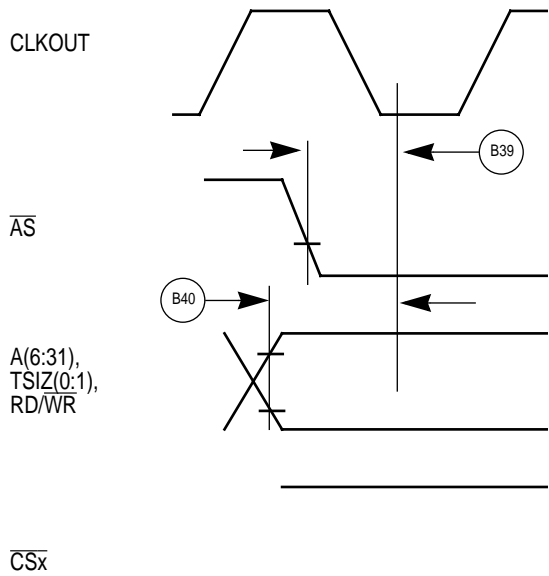


Figure 18. Asynchronous External I/O (GPCM Control)

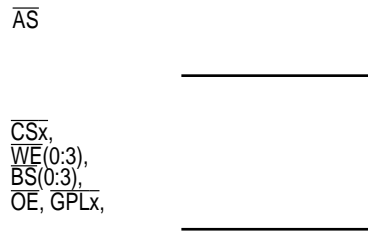


Figure 19. Asynchronous External I/O (Control Signals)

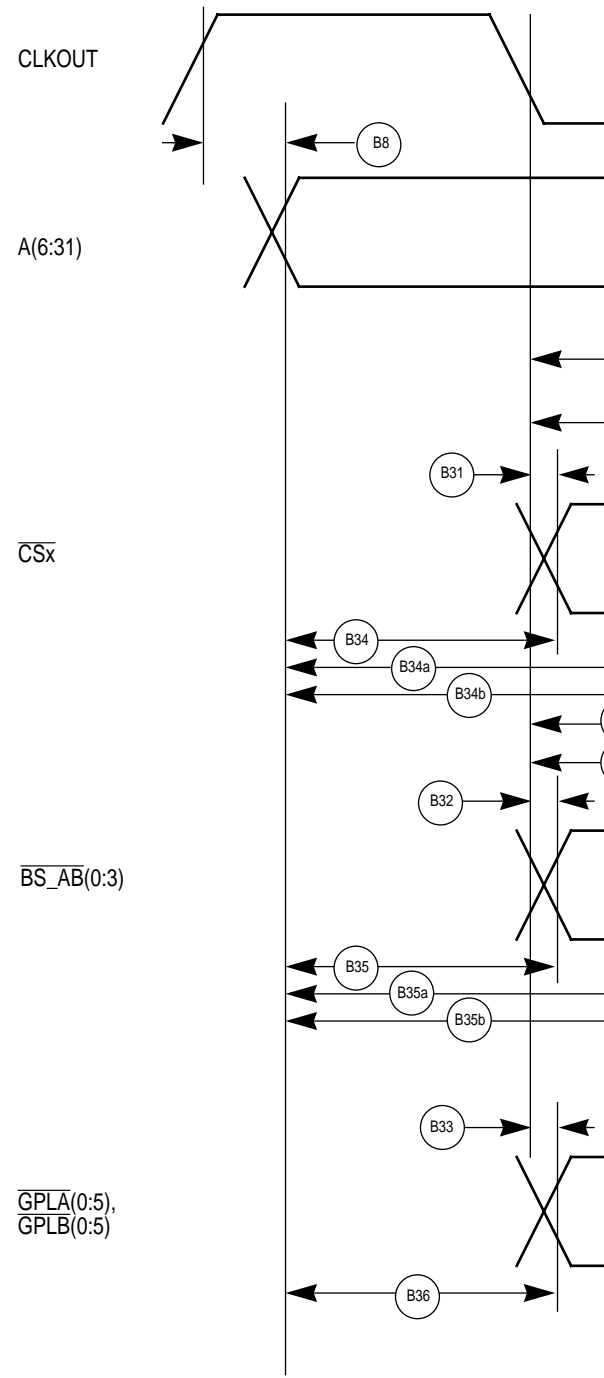


Figure 14. External Bus Timing

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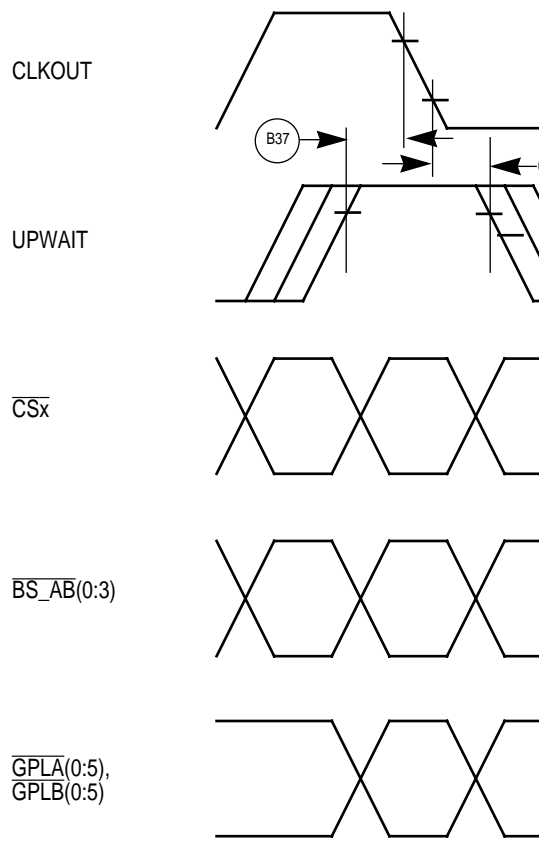


Figure 15. Asynchronous UP Handled Cycle

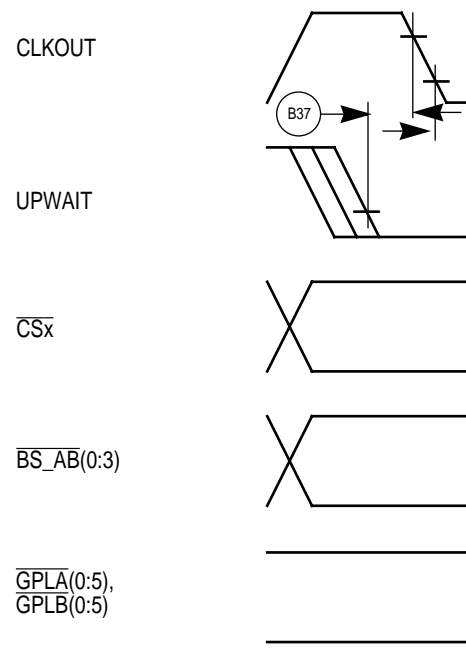


Figure 16. Asynchronous UP Handled Cycle

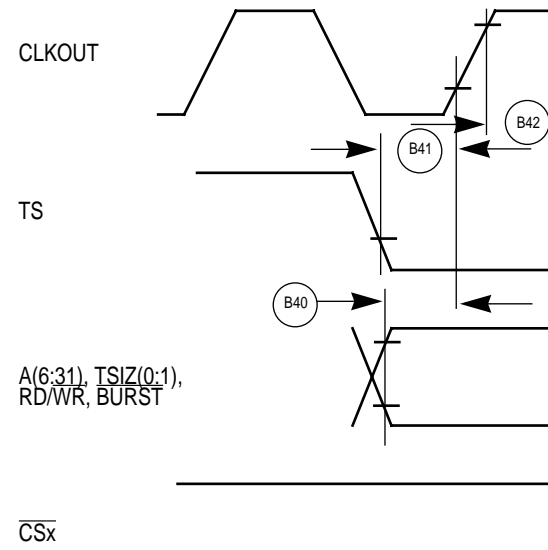


Figure 17. Synchronous External (GPCM Handled) Cycle

Table 2. In

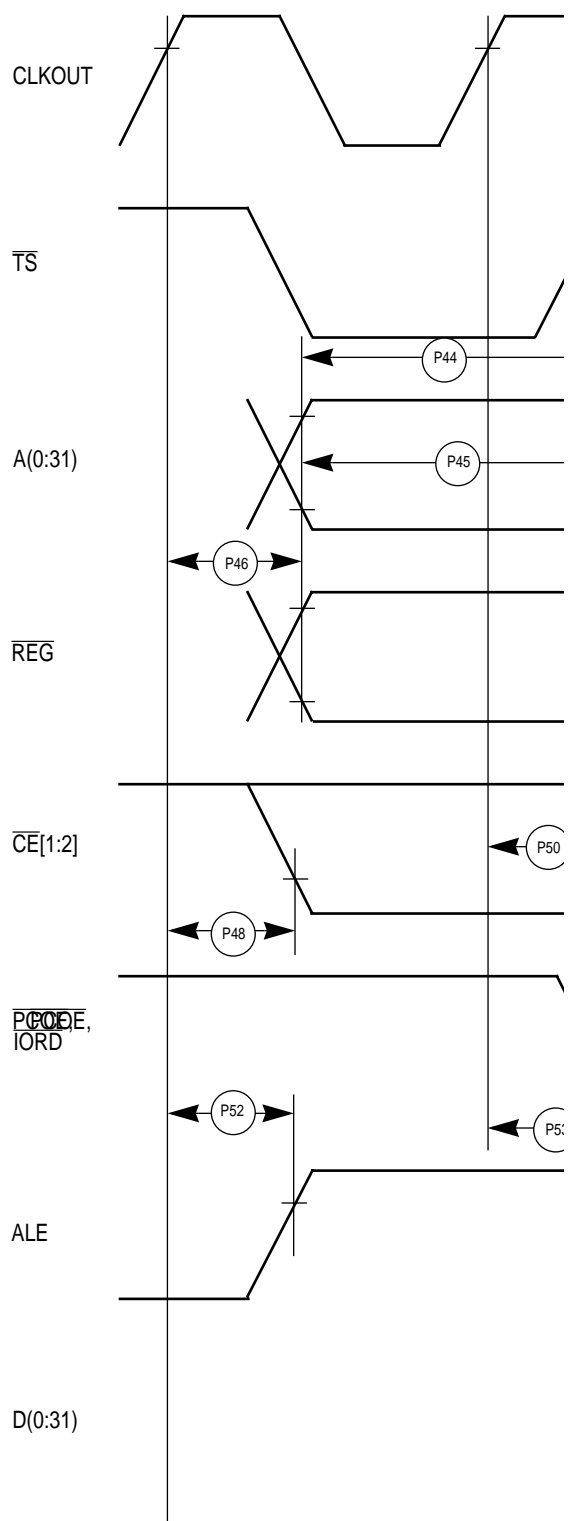


Figure 22. PCMCIA Access Cycle:

NUM	CHARACTERISTIC
I39	$\overline{\text{IRQx}}$ valid to CLKOUT rising edge (setup time)
I40	$\overline{\text{IRQx}}$ hold time after CLKOUT
I41	$\overline{\text{IRQx}}$ pulse width low
I42	$\overline{\text{IRQx}}$ pulse width high
I43	$\overline{\text{IRQx}}$ edge to edge time

NOTES:

1. The timings I39 and I40 describe the testing level sensitive. The $\overline{\text{IRQ}}$ lines are synchroni reference to the CLKOUT.
2. The timings I41 and I42 are specified to allow no direct relation with the total system inter

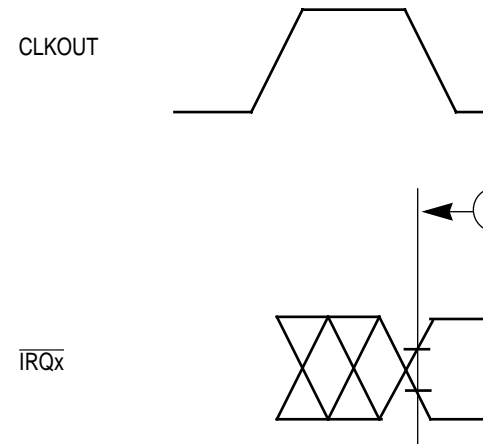


Figure 20. Interrupt D for External Le

Table 3. P

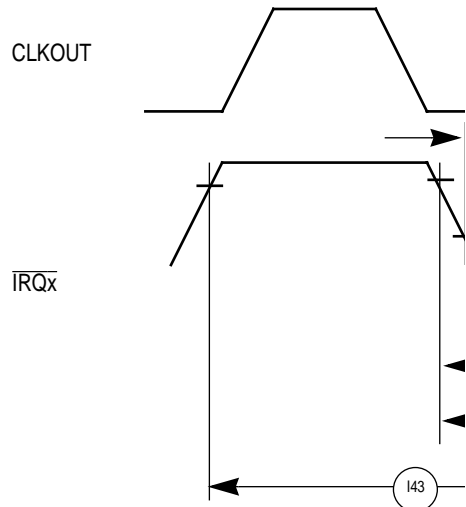


Figure 21. Interrupt I for External Ec

NUM	CHARACTERISTIC
P44	A(6:31), \overline{REG} valid to PCMCIA strobe asserted
P45	A(6:31), \overline{REG} valid to ALE negation
P46	CLKOUT to \overline{REG} valid
P47	CLKOUT to \overline{REG} invalid
P48	CLKOUT to $\overline{CE1}$, $\overline{CE2}$ asserted
P49	CLKOUT to $\overline{CE1}$, $\overline{CE2}$ negated
P50	CLKOUT to \overline{PCOE} , \overline{IORD} , \overline{PCWE} , \overline{IOWR} assert time
P51	CLKOUT to \overline{PCOE} , \overline{IORD} , \overline{PCWE} , \overline{IOWR} negate time
P52	CLKOUT to ALE assert time
P53	CLKOUT to ALE negate time
P54	\overline{PCWE} , \overline{IOWR} negated to D(0:31) invalid
P55	$\overline{WAIT_B}$ valid to CLKOUT rising edge
P56	CLKOUT rising edge to $\overline{WAIT_B}$ invalid

NOTES:

1. PSST = 1. Otherwise, add PSST times cycle.
2. PSHT = 0. Otherwise, add PSHT times cycle.
3. These synchronous timings define when the PCMCIA current cycle. The $\overline{WAIT_B}$ assertion timer expiration.

Table 5. De

NUM	CHARACTERISTIC
D61	DSCK cycle time
D62	DSCK clock pulse width
D63	DSCK rise and fall times
D64	DSDI input data setup time
D65	DSDI data hold time
D66	DSCK low to DSDO data valid
D67	DSCK low to DSDO invalid

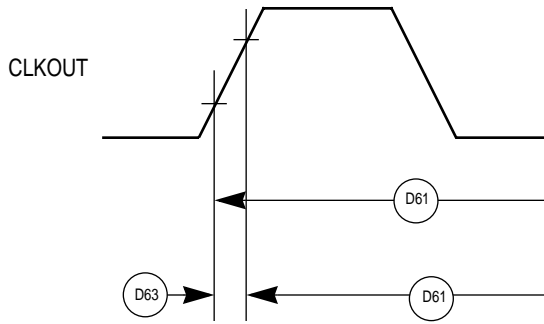


Figure 28. Debug Port

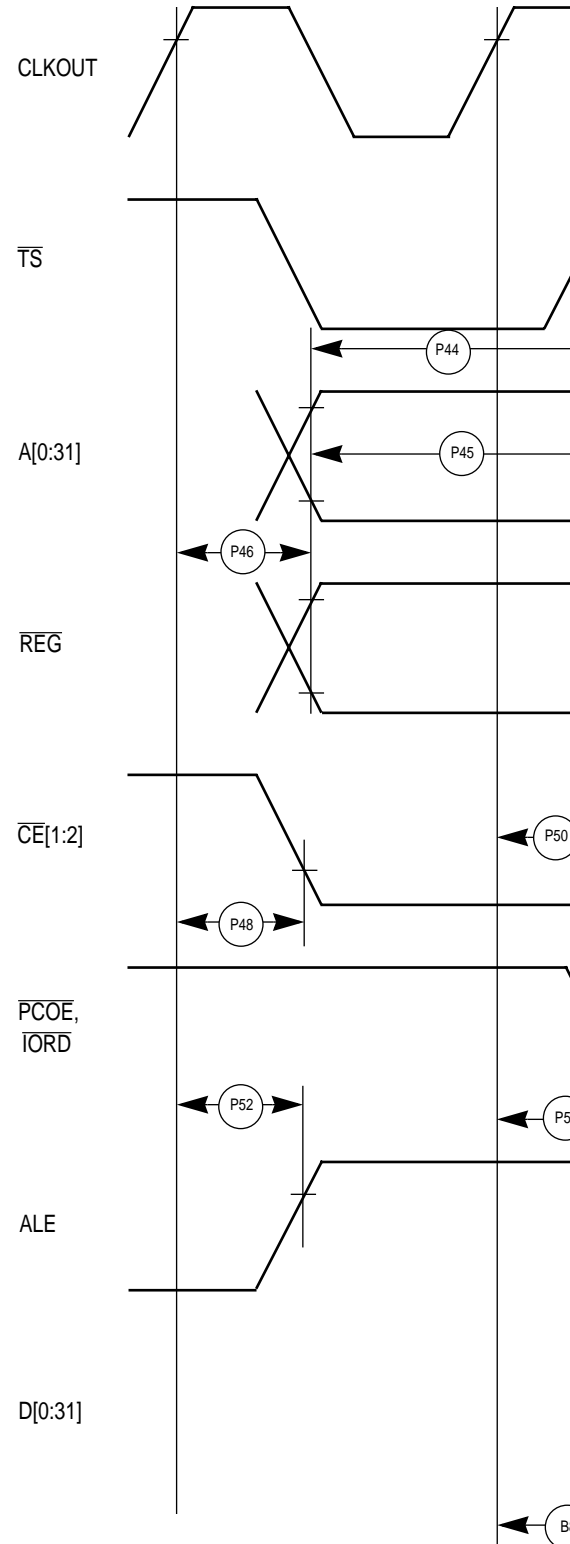


Figure 23. PCMCIA Access Cycles

Table 4. PCMCIA

NUM	CHARACTERISTIC
P57	CLKOUT to OPx Valid
P58	HRESET negated to OPx drive
P59	IP_Bx valid to CLKOUT Rising Edge
P60	CLKOUT Rising Edge to IP_Bx invalid

NOTE: *OP2 and OP3 only.

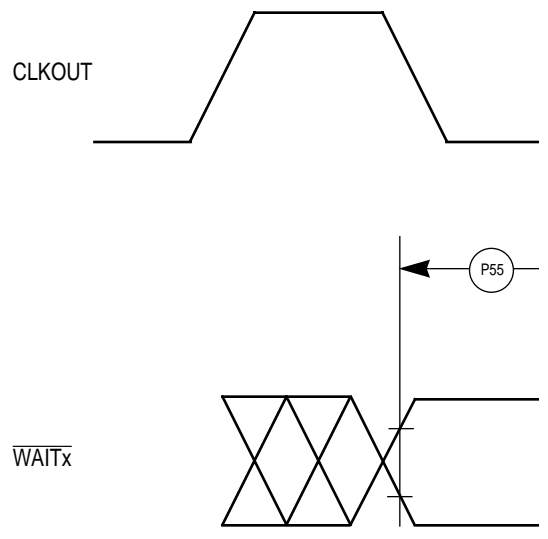


Figure 24. PCMCIA Wait Sig

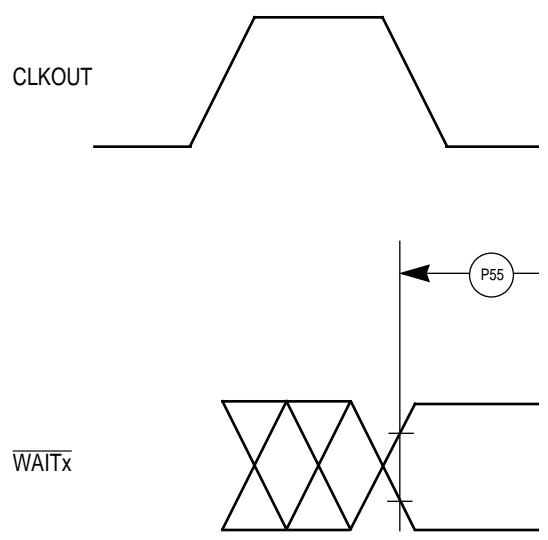


Figure 25. PCMCIA Wait Sig

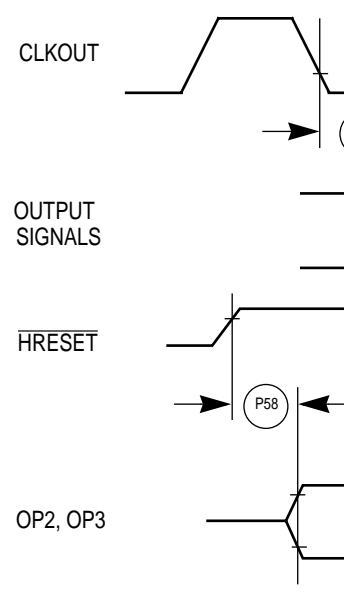


Figure 26. PCMCIA O

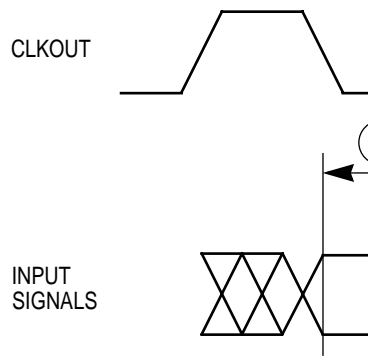


Figure 27. PCMCIA In

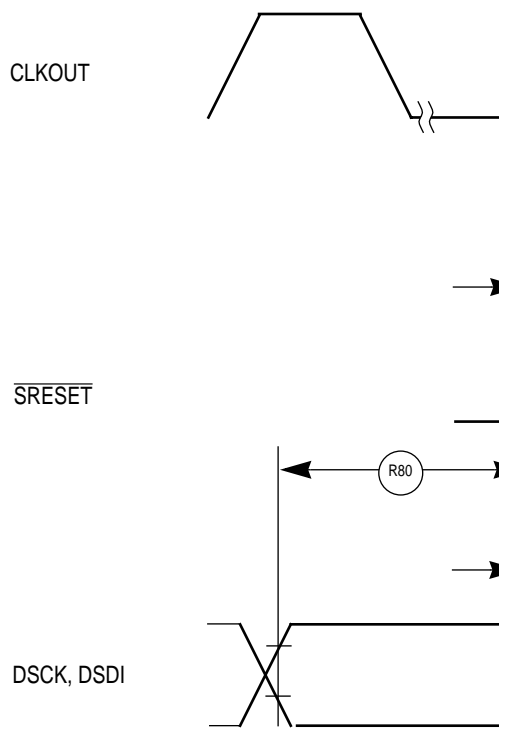


Figure 32. Reset Timing Dia

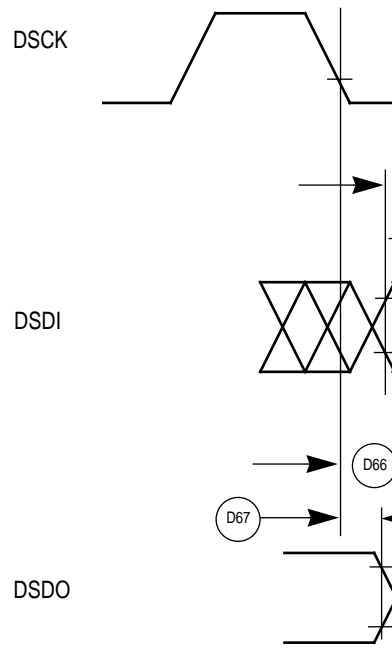


Figure 29. Debug

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Table 6.

NUM	CHARACTERISTIC
R68	CLKOUT to $\overline{\text{HRESET}}$ high impedance
R69	CLKOUT to $\overline{\text{SRESET}}$ high impedance
R70	$\overline{\text{RSTCONF}}$ pulse width
R71	N/A
R72	Configuration data to $\overline{\text{HRESET}}$ rising edge setup time
R73	Configuration data to $\overline{\text{RSTCONF}}$ rising edge setup time
R74	Configuration data hold time after $\overline{\text{RSTCONF}}$ negation
R75	Configuration data hold time after $\overline{\text{HRESET}}$ negation
R76	$\overline{\text{HRESET}}$ and $\overline{\text{RSTCONF}}$ asserted to data out driver
R77	$\overline{\text{RSTCONF}}$ negated to data out high impedance
R78	CLKOUT of last rising edge before chip three-state $\overline{\text{HRESET}}$ to data out high impedance
R79	DSDI and DSCK setup
R80	DSDI and DSCK hold time
R81	$\overline{\text{SRESET}}$ negated to CLKOUT rising edge for DS and DSCK sample

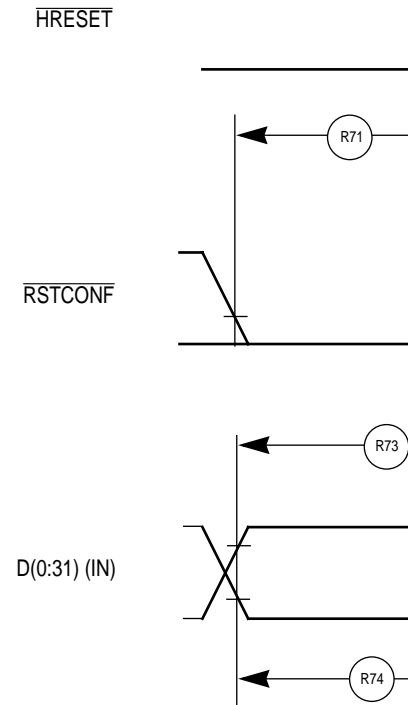


Figure 30. Reset Timing Diagram

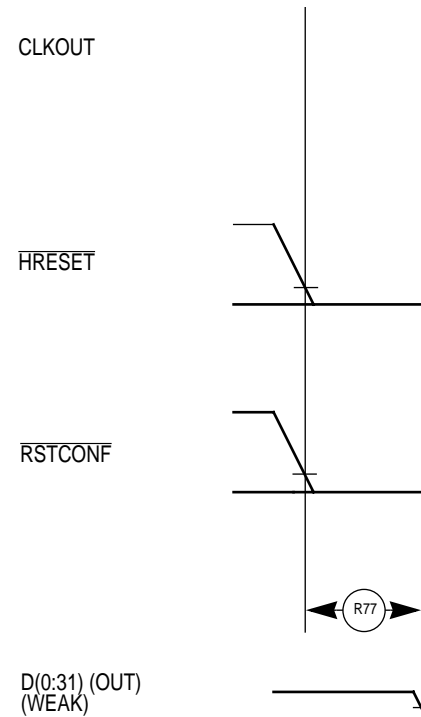


Figure 31. Reset Timing Diagram-MPC823

COMMUNICATION ELECTRICAL CHARACTERISTICS

Table 7.

Table 8. Parallel Input

NUM	CHARACTERISTIC	M
29	Data-in setup time to clock high	2
30	Data-in hold time from clock high	1
31	Clock high to data-out valid (CPU writes data, control, or direction)	-

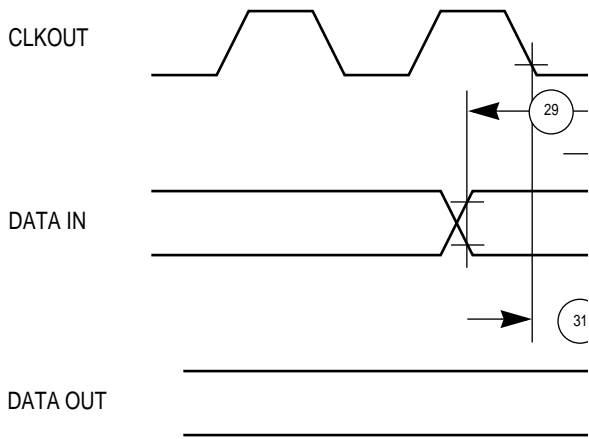


Figure 37. Parallel Input/Output

NUM	CHARACTERISTIC
J82	TCK cycle time
J83	TCK clock pulse width measured at 1.5V
J84	TCK rise and fall times
J85	TMS, TDI data setup time
J86	TMS, TDI data hold time
J87	TCK low to TDO data valid
J88	TCK low to TDO data invalid
J89	TCK low to TDO high impedance
J90	$\overline{\text{TRST}}$ assert time
J91	$\overline{\text{TRST}}$ setup time to TCK low
J92	TCK falling edge to output valid
J93	TCK falling edge to output valid out of high impedance
J94	TCK falling edge to output high impedance
J95	Boundary scan input valid to TCK rising edge
J96	TCK rising edge to boundary scan input invalid

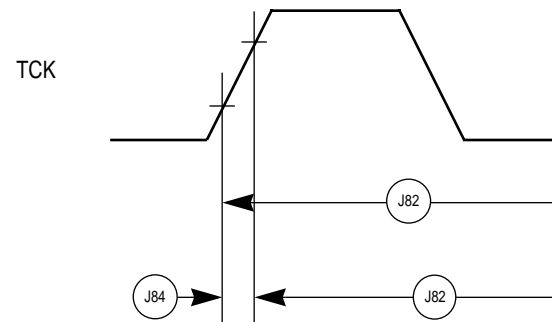


Figure 33. JTAG Test Clock

Freescale Semiconductor, Inc.

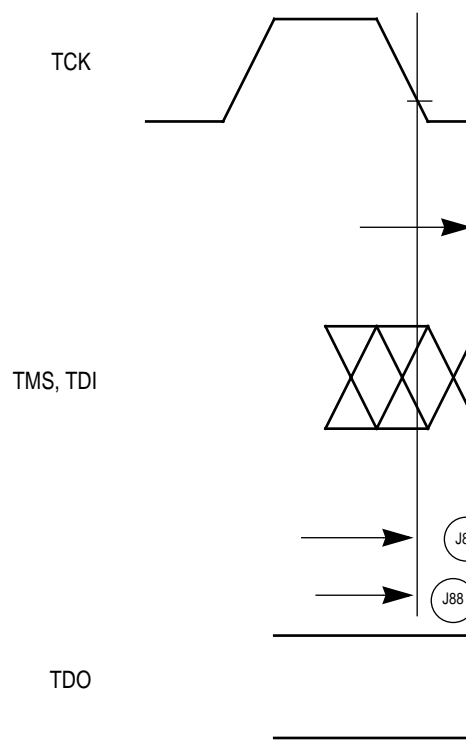


Figure 34. JTAG-Test A

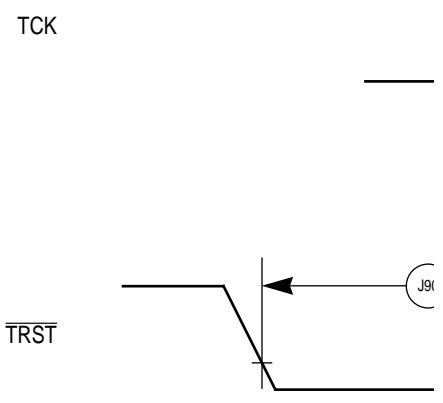


Figure 35. JTAG-TRST

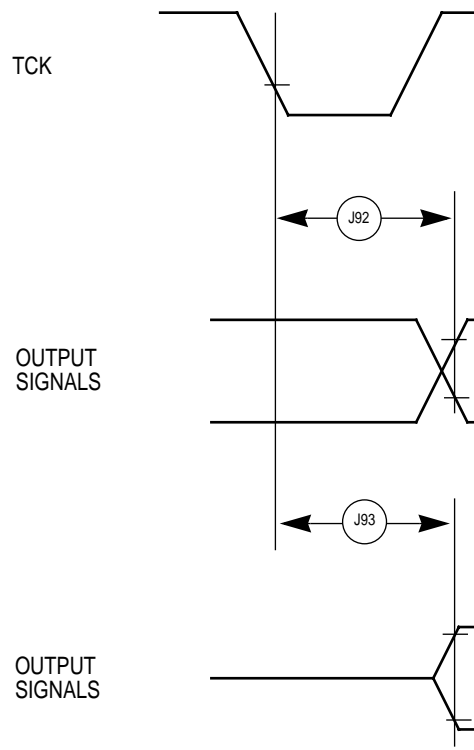


Figure 36. Boundary Scan

Table 9.

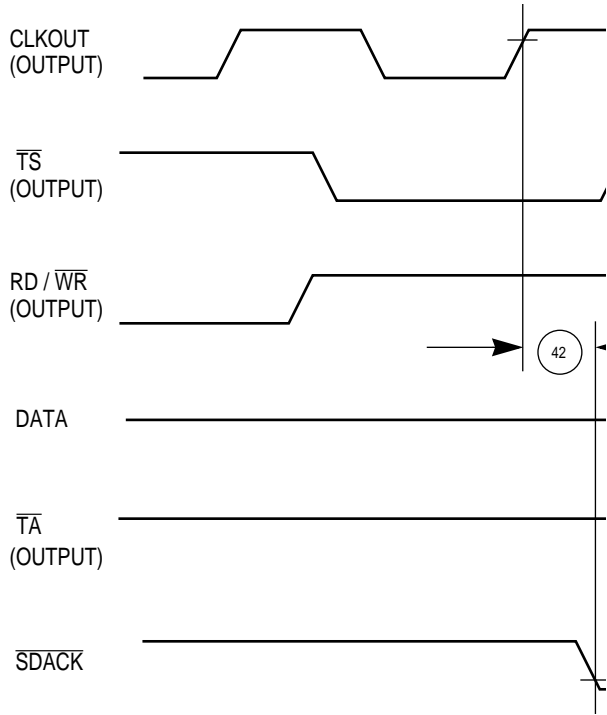


Figure 41. \overline{SDACK} Timin

NUM	CHARACTERISTIC	M
40	\overline{DREQ} setup time to clock high	1
41	\overline{DREQ} hold time from clock high	5
42	\overline{SDACK} assertion delay from clock high	-
43	\overline{SDACK} negation delay from clock low	-
44	\overline{SDACK} negation delay from \overline{TA} low	-
45	\overline{SDACK} negation delay from clock high	-
46	\overline{TA} assertion to falling edge of the clock setup time	1

NOTE: Applies to external \overline{TA} .

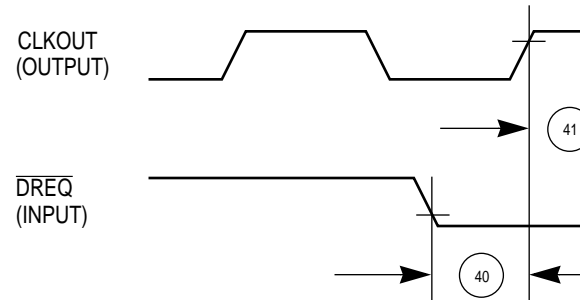


Figure 38. IDMA Extern

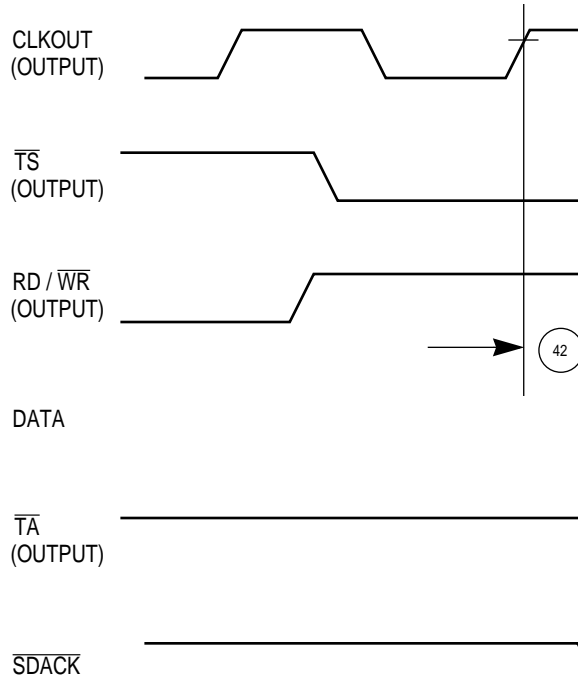


Figure 39. \overline{SDACK} Timing Diagram at the Falling

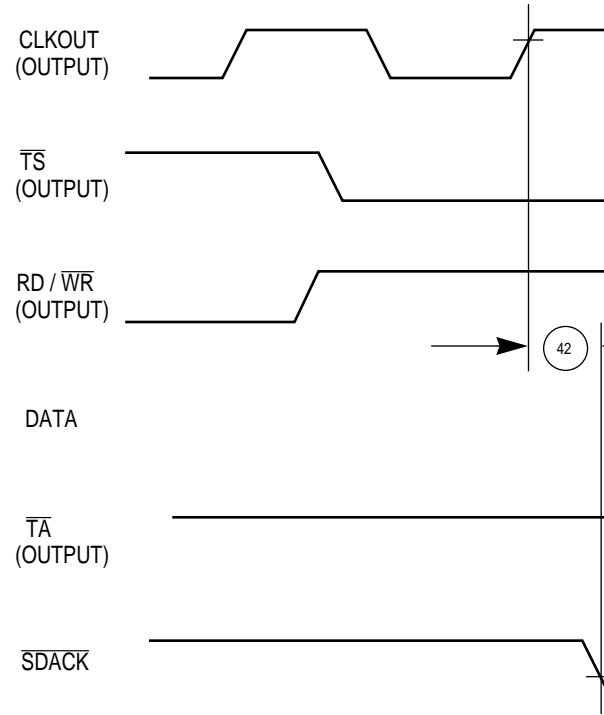


Figure 40. \overline{SDACK} Timing Diagram at the Falling

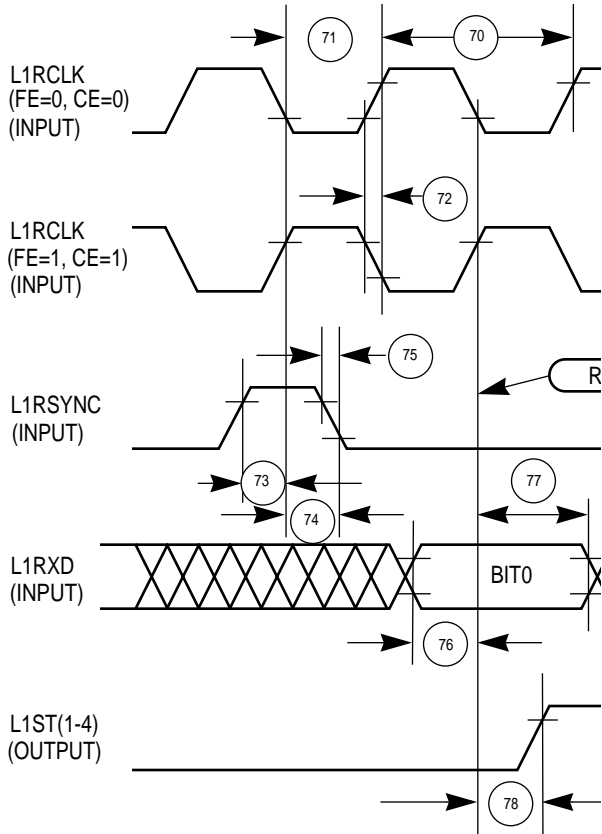


Figure 44. Serial Interface Receive Timi

Table 10. Baud R

NUM	CHARACTERISTIC	M
50	BRGO rise and fall times	—
51	BRGO duty cycle	4
52	BRGO cycle	4

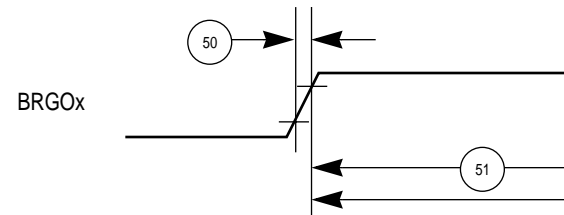


Figure 42. Baud Rate

Freescale Semiconductor, Inc.

Table 11. General-Purpose

NUM	CHARACTERISTIC	MIN
61	TIN/ $\overline{\text{TGATE}}$ rise and fall times	12
62	TIN/ $\overline{\text{TGATE}}$ low time	5
63	TIN/ $\overline{\text{TGATE}}$ high time	—
64	TIN/ $\overline{\text{TGATE}}$ cycle time	—
65	CLKO low to $\overline{\text{TOUT}}$ valid	—

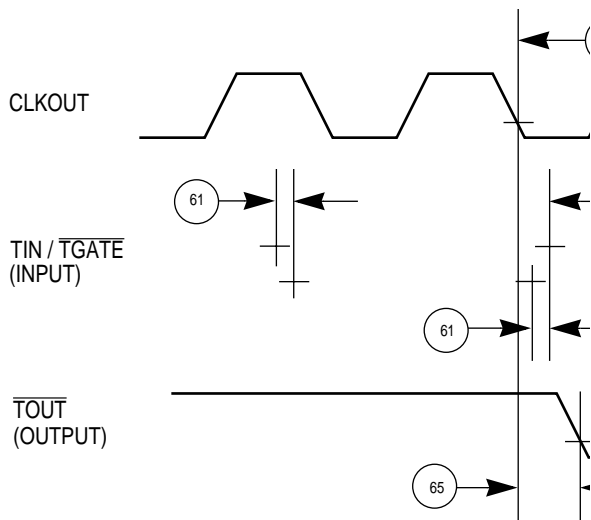


Figure 43. General-Purpose

Table 12. Serial

NUM	CHARACTERISTIC
70	L1RCLK and L1TCLK frequency (DSC=0) ^{1,3}
71	L1RCLK and L1TCLK width low (DSC=0) ³
71a	L1RCLK and L1TCLK width high (DSC=0) ²
72	L1TXD, L1ST(1–8), L1RQ, L1CLKO rise and fall times
73	L1RSYNC, L1TSYNC valid to L1CLK edge (SYNC setup time)
74	L1CLK edge to L1RSYNC and L1TSYNC invalid (SYNC hold time)
75	L1RSYNC and L1TSYNC rise and fall times
76	L1RXD valid to L1CLK edge (L1RXD setup time)
77	L1CLK edge to L1RXD invalid (L1RXD hold time)
78	L1CLK edge to L1ST(1–8) valid
78a	L1SYNC valid to L1ST(1–8) valid ⁴
79	L1CLK edge to L1ST(1–8) invalid
80	L1CLK edge to L1TXD valid
80a	L1TSYNC valid to L1TXD valid ⁴
81	L1CLK edge to L1TXD high impedance
82	L1RCLK and L1TCLK frequency (DSC=1)
83	L1RCLK and L1TCLK width low (DSC=1)
83a	L1RCLK and L1TCLK width high (DSC=1) ²
84	L1CLK edge to L1CLKO valid (DSC=1)
85	L1RQ valid before falling edge of L1TSYNC ³
86	L1GR setup time ³
87	L1GR hold time ³
88	L1CLK edge to L1SYNC valid (FSD = 00, CNT = 0000, BYT = 0, DSC=0)

NOTES:

1. The ratio SyncCLK/L1RCLK must be greater than 1.
2. Where P=1/CLKO1. For a 25MHz CLKO1 rate, P=40ns.
3. These electrical specifications are only valid for DSC=0.
4. The strobes and TXD2 on the first bit of the data is later.

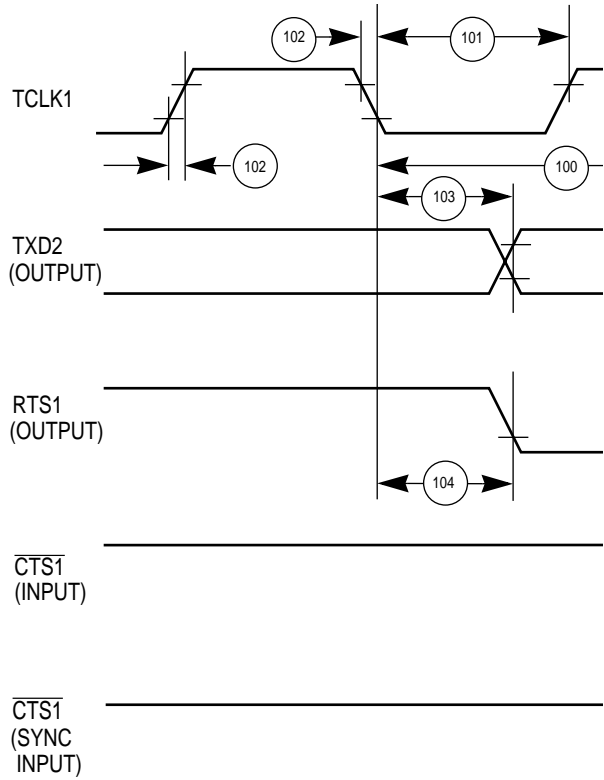


Figure 47. SCC NMSI

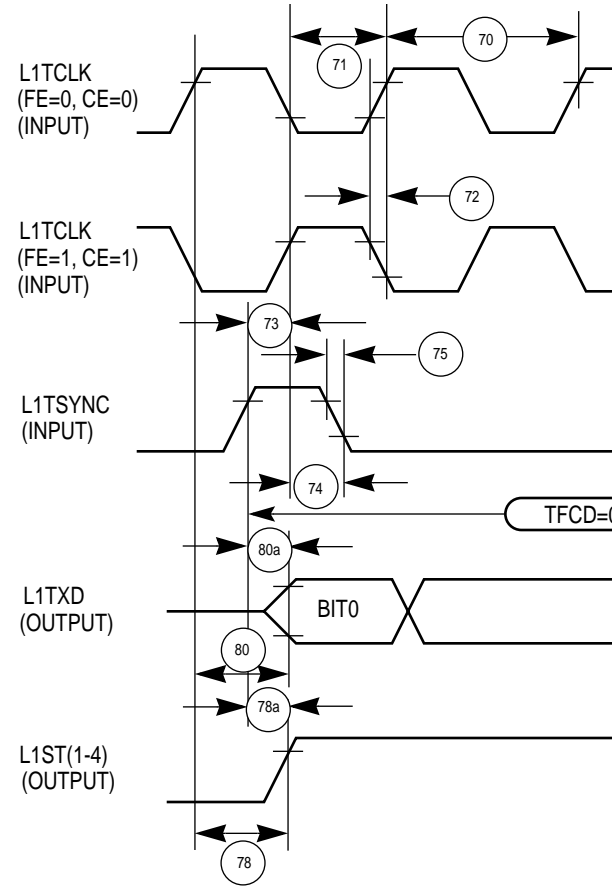


Figure 45. Serial Interface

Table 13. Serial Communication

NUM	CHARACTERISTIC	2
		MIN
100	RCLK1 and TCLK1 width high ¹	CLKOU F
101	RCLK1 and TCLK1 width low	CLKOU +5ns
102	RCLK1 and TCLK1 rise and fall times	—
103	TXD2 active delay (from TCLK1 falling edge)	0
104	$\overline{RTS1}$ active/inactive delay (from TCLK1 falling edge)	0
105	$\overline{CTS1}$ setup time to TCLK1 rising edge	5
106	RXD2 setup time to RCLK1 rising edge	5
107	RXD2 hold time from RCLK1 rising edge ²	5
108	$\overline{CD1}$ setup time to RCLK1 rising edge	5

NOTES:

1. The ratio SyncCLK/RCLK1 and SyncCLK/T
2. Applies to \overline{CD} and \overline{CTS} hold time when they

Table 14. Serial Communication

NUM	CHARACTERISTIC	MI
		MIN
100	RCLK1 and TCLK1 frequency ¹	C
102	RCLK1 and TCLK1 rise and all times	—
103	TXD2 active delay (from TCLK1 falling edge)	C
104	$\overline{RTS1}$ active/inactive delay (from TCLK1 falling edge)	C
105	$\overline{CTS1}$ setup time to TCLK1 rising edge	4
106	RXD2 setup time to RCLK1 rising edge	4
107	RXD2 hold time from RCLK1 rising edge ²	C
108	$\overline{CD1}$ setup time to RCLK1 rising edge	4

NOTES:

1. The ratio SyncCLK/RCLK1 and SyncCLK/T
2. Applies to \overline{CD} and \overline{CTS} hold time when the

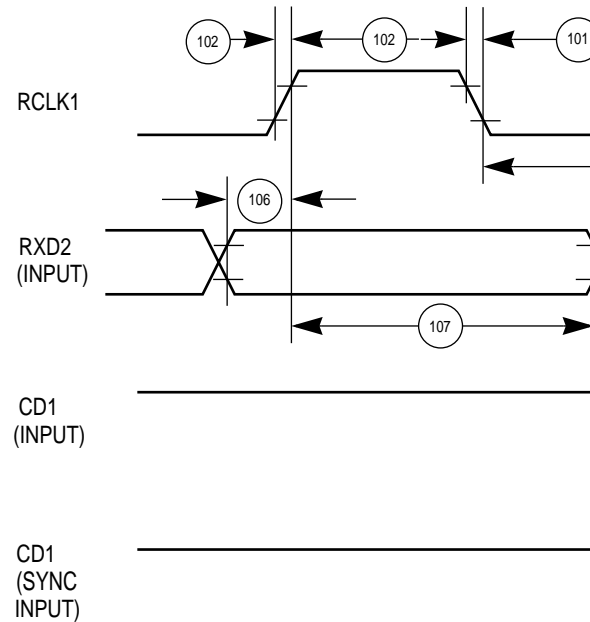
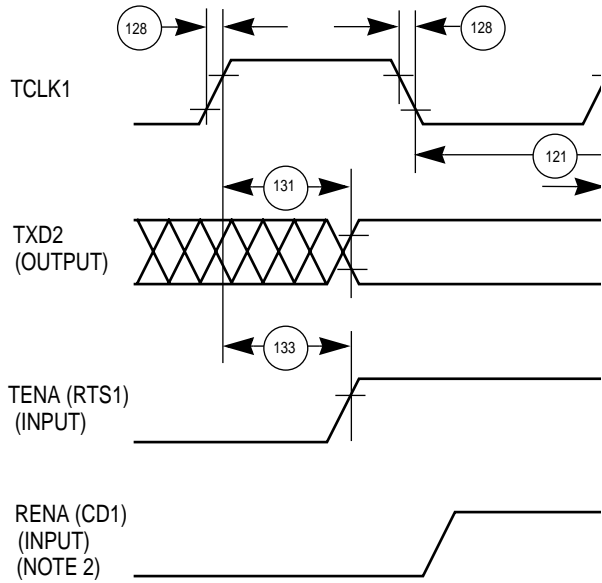


Figure 46. SCC NMS



NOTES: 1. TRANSMIT CLOCK INVERT (TCI) BIT IN THE GSMF
 2. IF RENA IS DEASSERTED BEFORE TENA, OR RENA TRANSMIT, THEN THE CSL BIT IS SET IN THE BUI

Figure 51. Ethernet

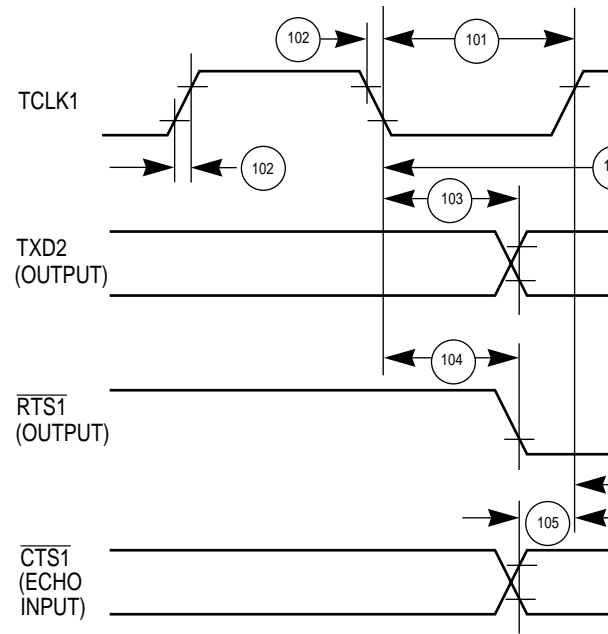


Figure 48. HDLC

Table 15. E

NUM	CHARACTERISTIC	M
120	CLSN (CTS2) width high	4
121	RCLK1 rise and fall times	-
122	RCLK1 width low	4
123	RCLK1 clock period ¹	8
124	RXD2 setup time	2
125	RXD2 hold time	4
126	RENA (CD2) active delay (from RCLK1 rising edge of the last data bit)	1
127	RENA (CD2) width low	10
128	TCLK1 rise and fall times	-
129	TCLK1 width low	4
130	TCLK1 clock period ¹	9
131	TXD2 active delay (from TCLK1 rising edge)	1
132	TXD2 inactive delay (from TCLK1 rising edge)	1
133	TENA (RTS2) active delay (from TCLK1 rising edge)	1
134	TENA (RTS2) inactive delay (from TCLK1 rising edge)	1
135	N/A	
136	N/A	
137	N/A	
138	CLKx low to SDACK asserted ²	-
139	CLKx low to SDACK negated ³	-

NOTES:

1. The ratio SyncCLK/RCLK1 and SyncCLK/TCLK1
2. SDACK is asserted when the SDMA writes

CLSN (CTS1)
(INPUT)

Figure 49. Ethernet

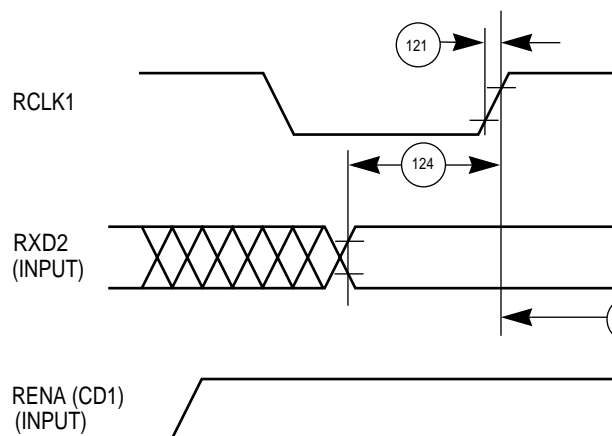


Figure 50. Ethernet

Table 16. Serial Peripheral

NUM	CHARACTERISTIC	MIN
160	Master cycle time	4
161	Master clock (SCK) high or low time	2
162	Master data setup time (inputs)	50
163	Master data hold time (inputs)	0
164	Master data valid (after SCK edge)	—
165	Master data hold time (outputs)	0
166	Rise time output	—
167	Fall time output	—

NOTE: The ratio SyncCLK/SMCLK must be greater than 1.

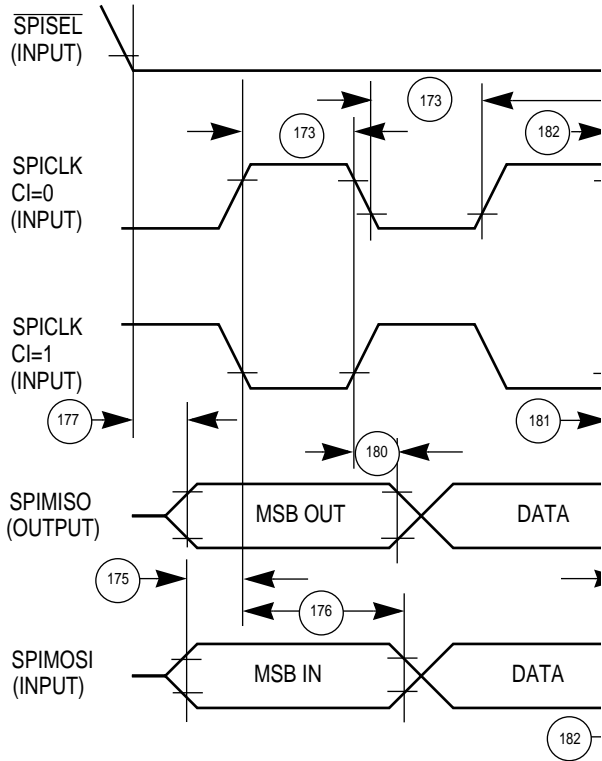


Figure 54. SPI Slave

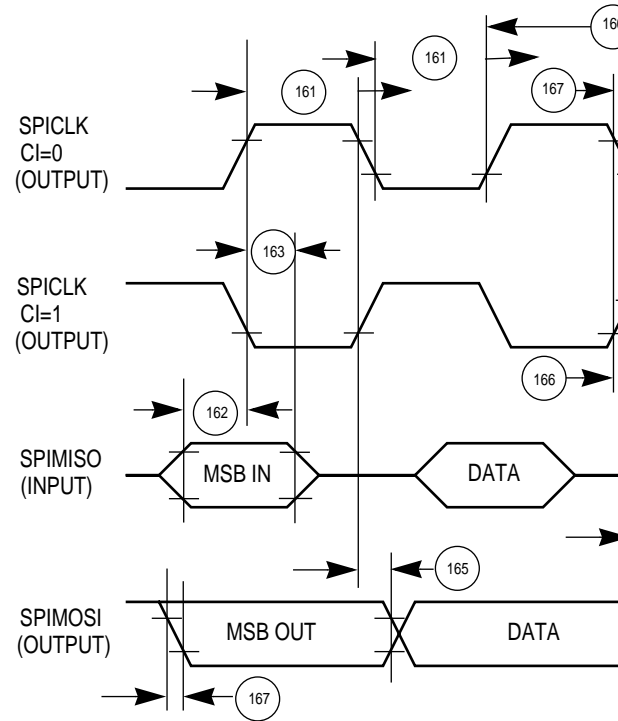


Figure 52. SPI Master

Table 17. Serial Periph

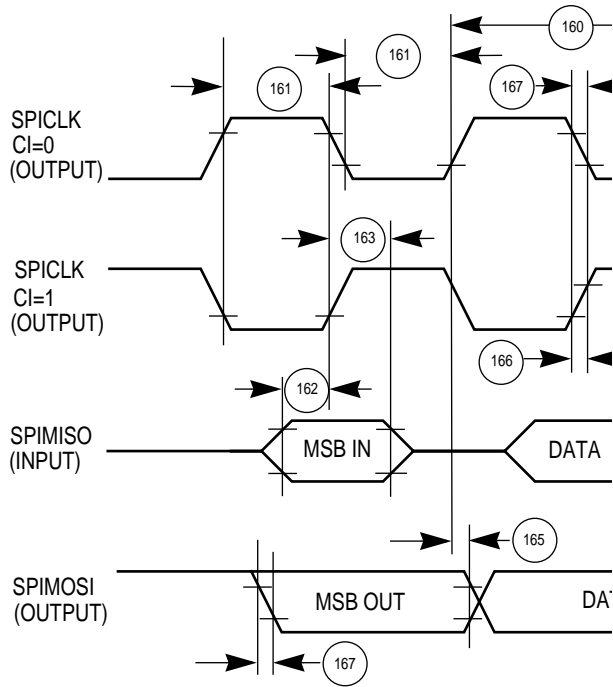


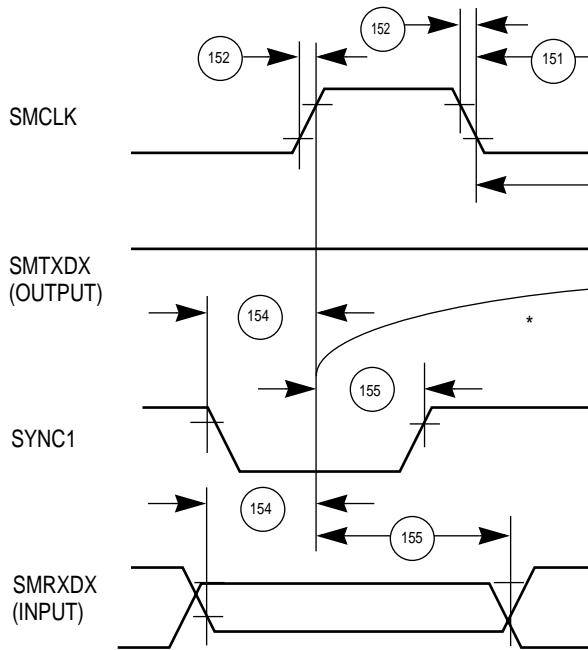
Figure 53. SPI Master

NUM	CHARACTERISTIC	M
170	Slave cycle time	2
171	Slave enable lead time	1
172	Slave enable lag time	1
173	Slave clock (SPICLK) high or low time	1
174	Slave sequential transfer delay (does not require deselect)	1
175	Slave data setup time (inputs)	2
176	Slave data hold time (inputs)	2
177	Slave access time	—
178	Slave SPI MISO disable time	—
179	Slave data valid (after SPICLK edge)	—
180	Slave data hold time (outputs)	0
181	Rise time (input)	—
182	Fall time (input)	—

Table 20. Serial Mana

NUM	CHARACTERISTIC	M
150	CLK1 clock period	10
151	CLK1 width low	5
151A	CLK1 width high	5
152	CLK1 rise and fall times	-
153	SMTXDx active delay (from CLK1 falling edge)	1
154	SMRXDx/SYNC1 setup time	2
155	SMRXDx/SYNC1 hold time	5

NOTE: The ratio SyncCLK/SMCLK must be greater than



NOTE: * THIS DELAY IS EQUAL TO AN INTEGER NUMBER OF

Figure 57. SMC Tran

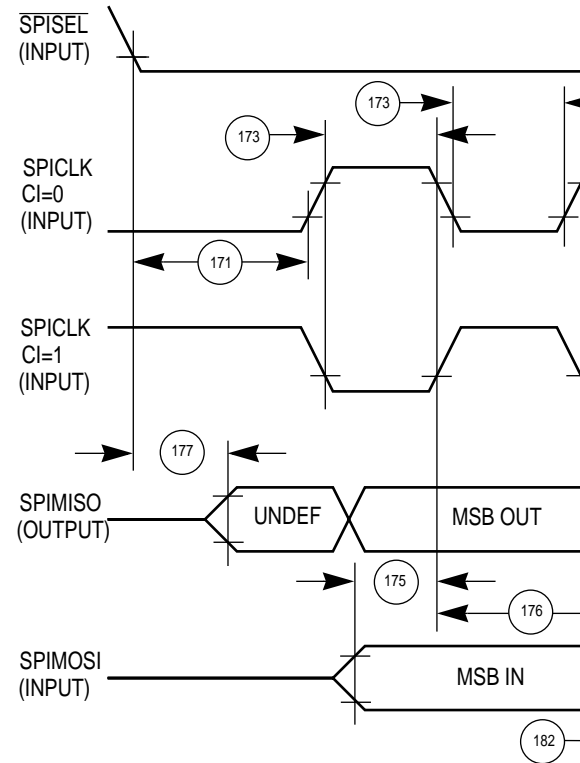


Figure 55. SPI Slave

Table 18. I²C Tim

NUM	CHARACTERISTIC	MIN
200	SCL clock frequency (slave)	0
200	SCL clock frequency (master)	1.5
202	Bus free time between transmissions	4.7
203	Low period of SCL	4.7
204	High period of SCL	4.0
205	Start condition setup time	4.7
206	Start condition hold time	4.0
207	Data hold time	0
208	Data setup time	250
209	SDL/SCL rise time	—
210	SDL/SCL fall time	—
211	STOP condition setup time	4.7

NOTE: SCL frequency is given by $SCL = BRGCLK_fre$
The ratio $SyncClk/(BRGCLK/pre_scaler)$ must be

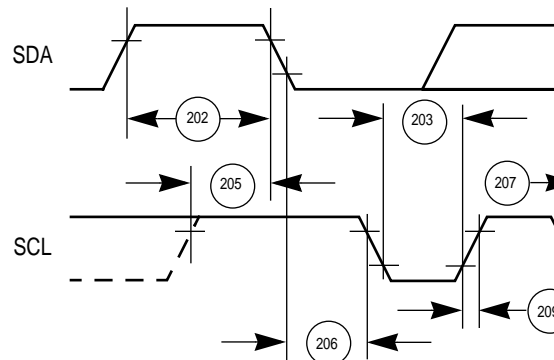


Figure 56. I²C E

Table 19. I²C Tim

NUM	CHARACTERISTIC
200	SCL clock frequency (slave)
200	SCL clock frequency (master)
202	Bus free time between transmissions
203	Low period of SCL
204	High period of SCL
205	Start condition setup time
206	Start condition hold time
207	Data hold time
208	Data setup time
209	SDL/SCL rise time
210	SDL/SCL fall time
211	Stop condition setup time

Table 22. Video

NUM	CHARACTERISTIC	MIN
		240
241	Clock high time	13
242	CLK/HSYNC/VSYNC/BLANK/FIELD rise and fall times	—
243	Clock high to data valid	10

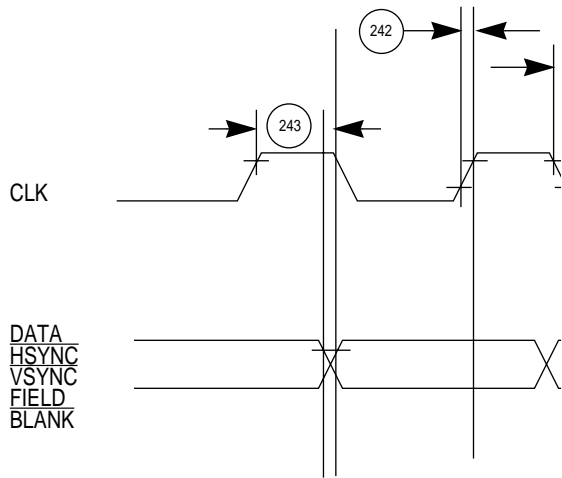


Figure 60. Video

Table 21. LCD

NUM	CHARACTERISTIC	MIN
		220
221	Shift clock high time	2
223	CLOCK/HSYNC/VSYNC/ \overline{OE} rise and fall times	—
224	Data valid delay from shift clock high	—
225	VSYNC to HSYNC setup time ¹	5
226	VSYNC hold time	1
227	HSYNC pulse width	4
228	Time from clock falling edge to HSYNC rising edge	4
229	Time from HSYNC falling edge to clock rising edge ²	4
230	AC active delay	—
231	VSYNC pulse width (TFT)	1
232	HSYNC to \overline{OE} delay ³	4
233	\overline{OE} to HSYNC delay	4
234	VSYNC to \overline{OE} delay (TFT)	0
235	VSYNC/HSYNC/ \overline{OE} active delay (TFT)	—
236	Wait between frames ⁴	W

NOTES:

1. T = shift clock cycle (220).
2. This number is given for wbl(wait between lines).
3. This number is given for wbl(wait between lines).
4. Wait Between Frames (WBF) is a programmed delay.

T_{cy} is the cycle time of the LCD clock (shift clock). The AC electrical specifications are for 1–16 lines and 16, depending on how the LCD controller is configured. 0–1,023 lines is a time period that can vary based on the LCVCR.

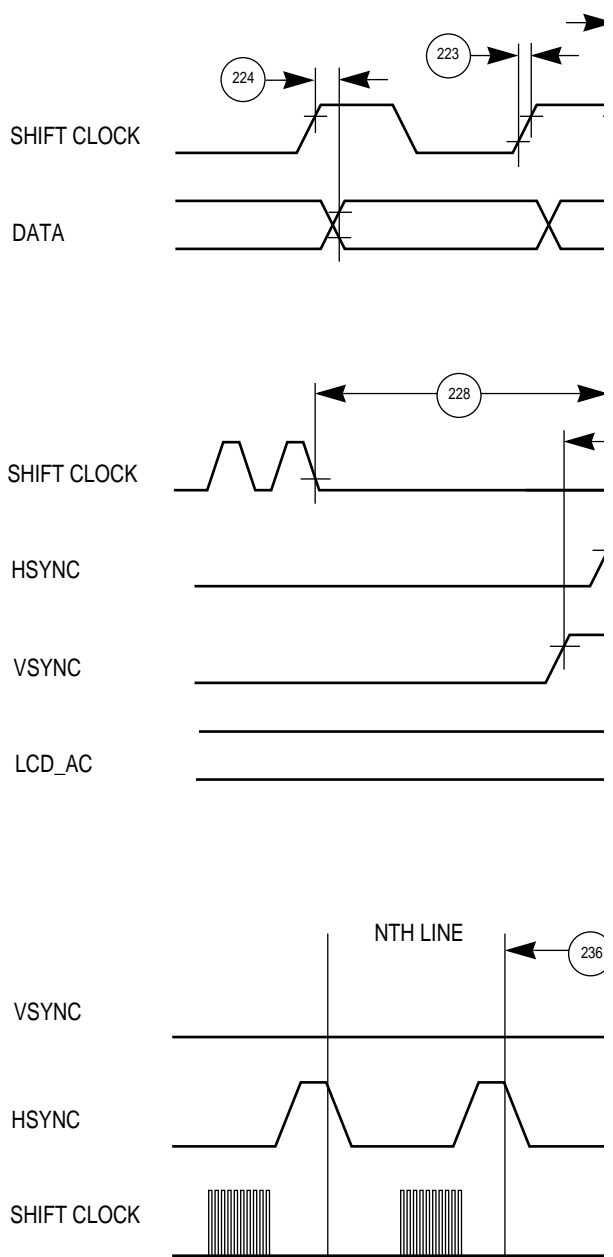


Figure 58. Passive

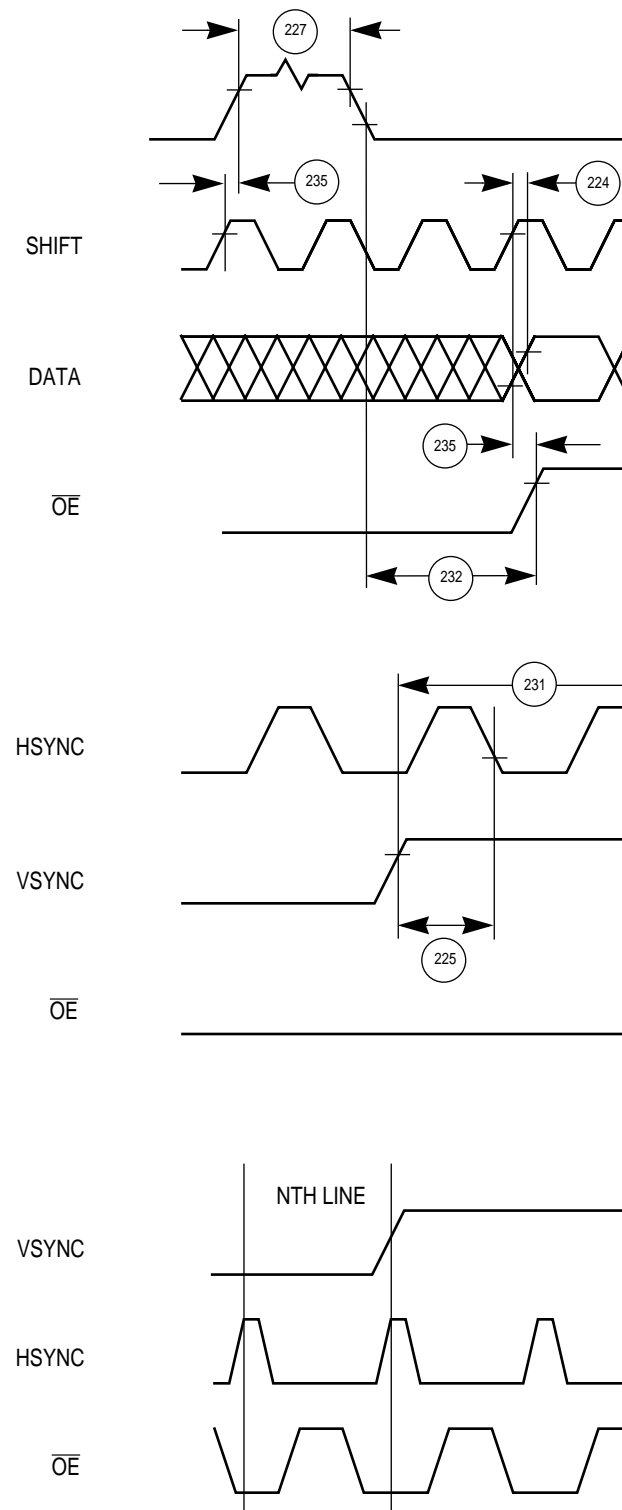


Figure 59. TFT P



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